

Search Notes



Application/Control No.

10/007,196

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

HARTER ET AL.

Art Unit

3629

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
| 705 | x 1 | 3/06 | DN |
| | 7 | | |
| | 8 | | |
| | 9 | | |
| | 10 | | |
| | x 26 | | |
| 717 | 121 | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |

INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

| | DATE | EXMR |
|------------|------|------|
| I US | 3/06 | DN |
| 1. PG Pub | | |
| 2. Patent | | |
| II FOREIGN | | |
| 1. EPO | | |
| 2. JPO | | |
| 3. IBM-TDB | | |
| 4. Derwent | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |